

IS61NLP6432A

IS61NLP6436A/IS61NVP6436A

IS61NLP12818A/IS61NVP12818A



64K x 32, 64K x 36, and 128K x 18
2Mb, PIPELINE 'NO WAIT' STATE BUS SRAM

PRELIMINARY INFORMATION
SEPTEMBER 2005

FEATURES

- 100 percent bus utilization
- No wait cycles between Read and Write
- Internal self-timed write cycle
- Individual Byte Write Control
- Single R/W (Read/Write) control pin
- Clock controlled, registered address, data and control
- Interleaved or linear burst sequence control using MODE input
- Three chip enables for simple depth expansion and address pipelining
- Power Down mode
- Common data inputs and data outputs
- $\overline{\text{CKE}}$ pin to enable clock and suspend operation
- JEDEC 100-pin TQFP package
- Power supply:
 NVP: V_{DD} 2.5V ($\pm 5\%$), V_{DDQ} 2.5V ($\pm 5\%$)
 NLP: V_{DD} 3.3V ($\pm 5\%$), V_{DDQ} 3.3V/2.5V ($\pm 5\%$)
- Industrial temperature available
- Lead-free available

DESCRIPTION

The 2 Meg 'NLP/NVP' product family feature high-speed, low-power synchronous static RAMs designed to provide a burstable, high-performance, 'no wait' state, device for networking and communications applications. They are organized as 64K words by 32 bits, 64K words by 36 bits, and 128K words by 18 bits, fabricated with ISSI's advanced CMOS technology.

Incorporating a 'no wait' state feature, wait cycles are eliminated when the bus switches from read to write, or write to read. This device integrates a 2-bit burst counter, high-speed SRAM core, and high-drive capability outputs into a single monolithic circuit.

All synchronous inputs pass through registers are controlled by a positive-edge-triggered single clock input. Operations may be suspended and all synchronous inputs ignored when Clock Enable, $\overline{\text{CKE}}$ is HIGH. In this state the internal device will hold their previous values.

All Read, Write and Deselect cycles are initiated by the ADV input. When the ADV is HIGH the internal burst counter is incremented. New external addresses can be loaded when ADV is LOW.

Write cycles are internally self-timed and are initiated by the rising edge of the clock inputs and when $\overline{\text{WE}}$ is LOW. Separate byte enables allow individual bytes to be written.

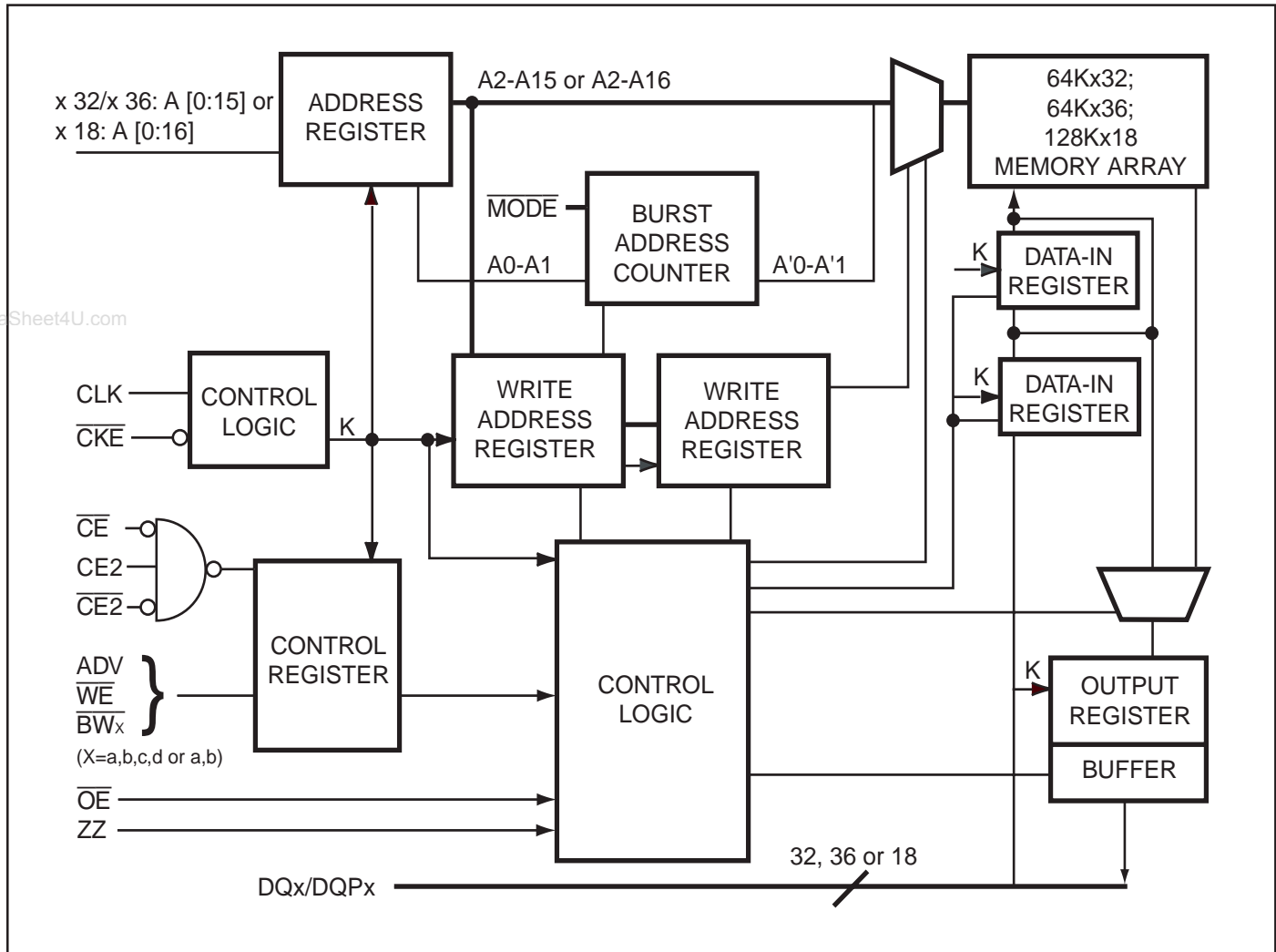
A burst mode pin (MODE) defines the order of the burst sequence. When tied HIGH, the interleaved burst sequence is selected. When tied LOW, the linear burst sequence is selected.

FAST ACCESS TIME

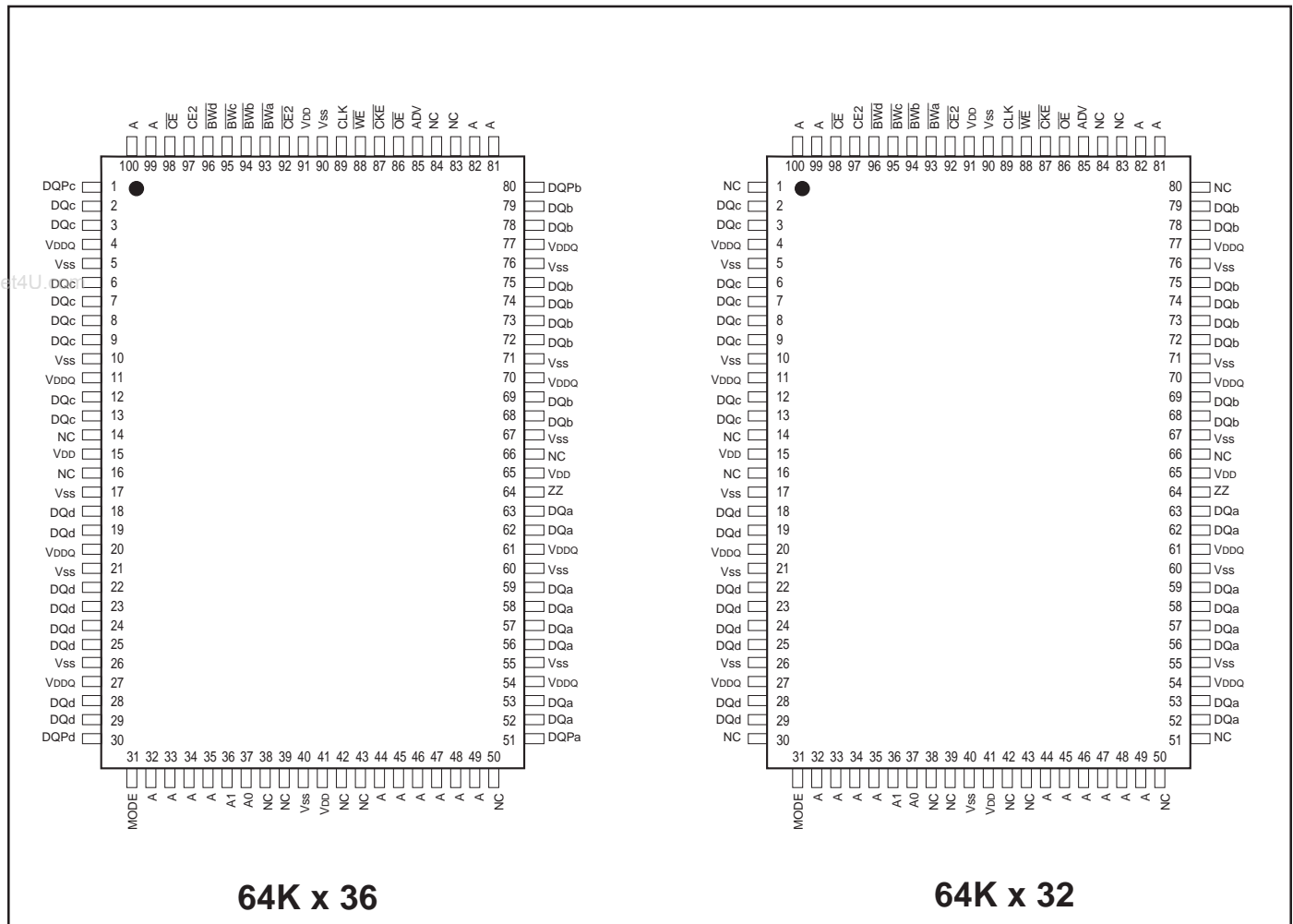
Symbol	Parameter	-250	-200	Units
tkQ	Clock Access Time	2.6	3.1	ns
tkC	Cycle Time	4	5	ns
	Frequency	250	200	MHz

Copyright © 2005 Integrated Silicon Solution, Inc. All rights reserved. ISSI reserves the right to make changes to this specification and its products at any time without notice. ISSI assumes no liability arising out of the application or use of any information, products or services described herein. Customers are advised to obtain the latest version of this device specification before relying on any published information and before placing orders for products.

BLOCK DIAGRAM



PIN CONFIGURATION
100-Pin TQFP



64K x 36

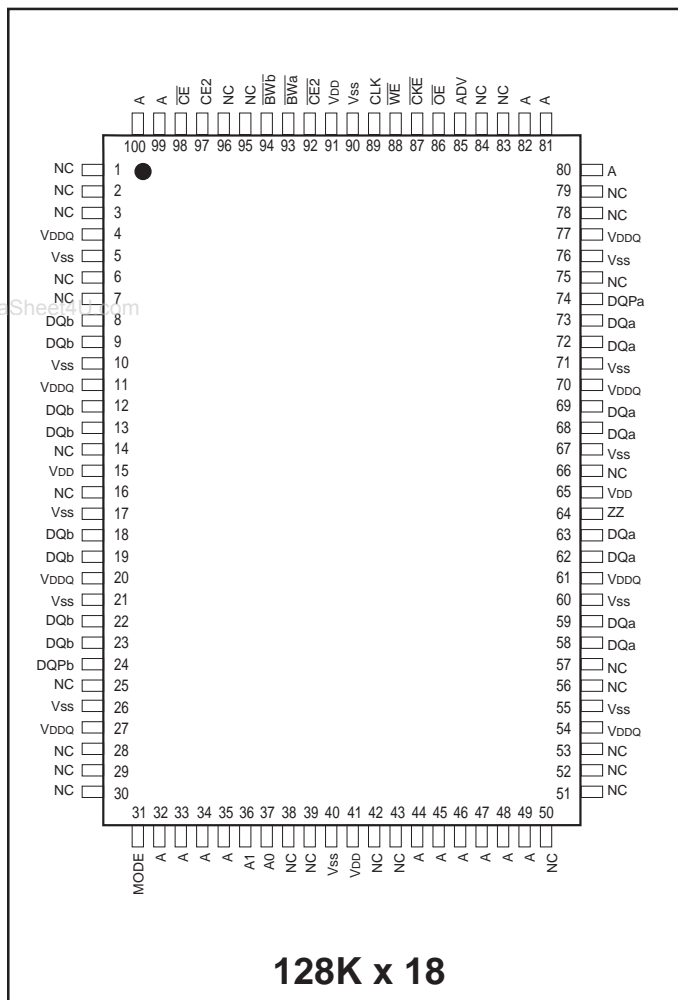
64K x 32

PIN DESCRIPTIONS

A0, A1	Synchronous Address Inputs. These pins must be tied to the two LSBs of the address bus.
A	Synchronous Address Inputs
CLK	Synchronous Clock
ADV	Synchronous Burst Address Advance
BW \bar{a} -BW \bar{d}	Synchronous Byte Write Enable
WE	Write Enable
CKE	Clock Enable
Vss	Ground for Core
NC	Not Connected

CE, CE2, CE $\bar{2}$	Synchronous Chip Enable
OE	Output Enable
DQa-DQd	Synchronous Data Input/Output
DQPa-DQPd	Parity Data I/O
MODE	Burst Sequence Selection
VDD	+3.3V/2.5V Power Supply
VSS	Ground for output Buffer
VDDQ	Isolated Output Buffer Supply: +3.3V/2.5V
ZZ	Snooze Enable

PIN CONFIGURATION
100-Pin TQFP

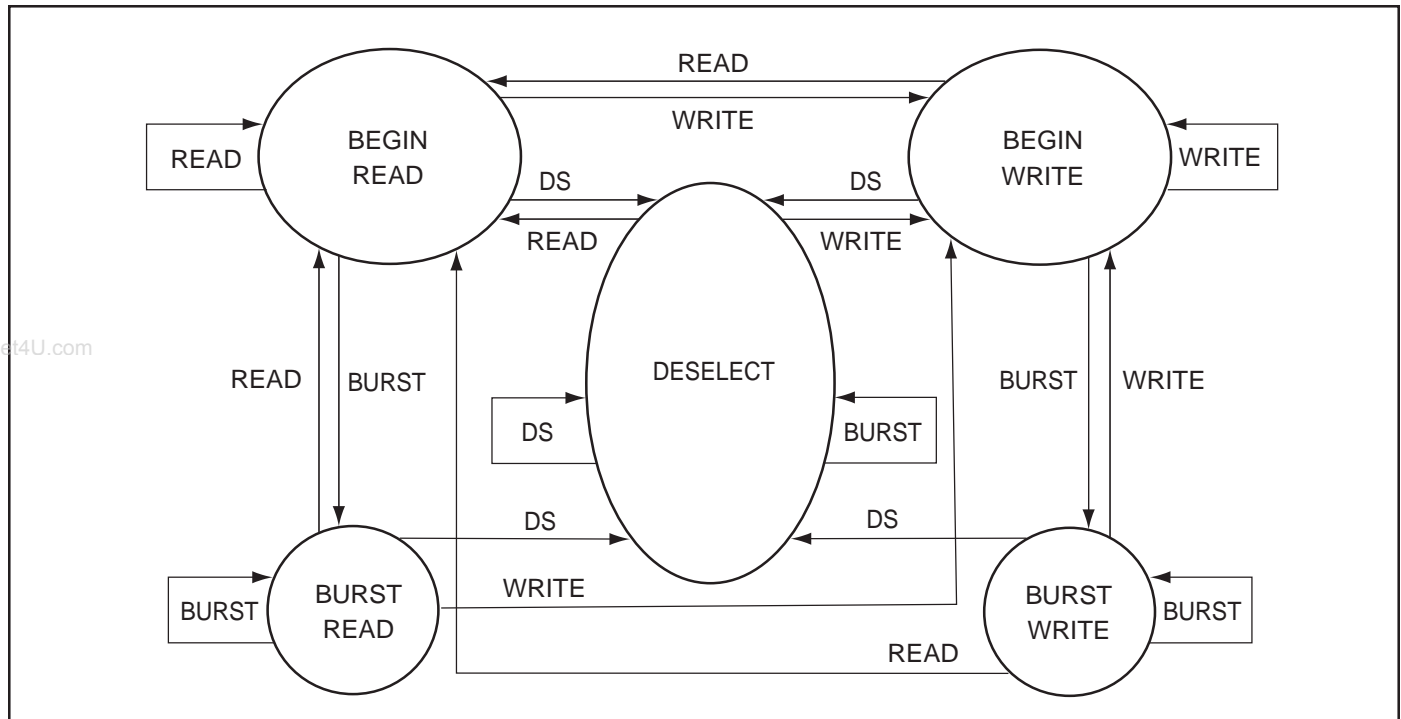


PIN DESCRIPTIONS

A0, A1	Synchronous Address Inputs. These pins must tied to the two LSBs of the address bus.
A	Synchronous Address Inputs
CLK	Synchronous Clock
ADV	Synchronous Burst Address Advance
BWa-BWd	Synchronous Byte Write Enable
WE	Write Enable
CKE	Clock Enable
Vss	Ground for Core
NC	Not Connected

CE, CE2, CE2	Synchronous Chip Enable
OE	Output Enable
DQa-DQd	Synchronous Data Input/Output
DQPa-DQPd	Parity Data I/O
MODE	Burst Sequence Selection
VDD	+3.3V/2.5V Power Supply
Vss	Ground for output Buffer
VDDQ	Isolated Output Buffer Supply: +3.3V/2.5V
ZZ	Snooze Enable

STATE DIAGRAM



SYNCHRONOUS TRUTH TABLE⁽¹⁾

Operation	Address Used	\overline{CE}	CE2	$\overline{CE2}$	ADV	\overline{WE}	$\overline{BW_x}$	\overline{OE}	\overline{CKE}	CLK
Not Selected	N/A	H	X	X	L	X	X	X	L	↑
Not Selected	N/A	X	L	X	L	X	X	X	L	↑
Not Selected	N/A	X	X	H	L	X	X	X	L	↑
Not Selected Continue	N/A	X	X	X	H	X	X	X	L	↑
Begin Burst Read	External Address	L	H	L	L	H	X	L	L	↑
Continue Burst Read	Next Address	X	X	X	H	X	X	L	L	↑
NOP/Dummy Read	External Address	L	H	L	L	H	X	H	L	↑
Dummy Read	Next Address	X	X	X	H	X	X	H	L	↑
Begin Burst Write	External Address	L	H	L	L	L	L	X	L	↑
Continue Burst Write	Next Address	X	X	X	H	X	L	X	L	↑
NOP/Write Abort	N/A	L	H	L	L	L	H	X	L	↑
Write Abort	Next Address	X	X	X	H	X	H	X	L	↑
Ignore Clock	Current Address	X	X	X	X	X	X	X	H	↑

Notes:

- "X" means don't care.
- The rising edge of clock is symbolized by ↑
- A continue deselect cycle can only be entered if a deselect cycle is executed first.
- $\overline{WE} = L$ means Write operation in Write Truth Table.
 $\overline{WE} = H$ means Read operation in Write Truth Table.
- Operation finally depends on status of asynchronous pins (\overline{ZZ} and \overline{OE}).

ASYNCHRONOUS TRUTH TABLE⁽¹⁾

Operation	ZZ	\overline{OE}	I/O STATUS
Sleep Mode	H	X	High-Z
Read	L	L	DQ
	L	H	High-Z
Write	L	X	Din, High-Z
Deselected	L	X	High-Z

Notes:

1. X means "Don't Care".
2. For write cycles following read cycles, the output buffers must be disabled with \overline{OE} , otherwise data bus contention will occur.
3. Sleep Mode means power Sleep Mode where stand-by current does not depend on cycle time.
4. Deselected means power Sleep Mode where stand-by current depends on cycle time.

WRITE TRUTH TABLE (x18)

Operation	WE	\overline{BW}_a	\overline{BW}_b
READ	H	X	X
WRITE BYTE a	L	L	H
WRITE BYTE b	L	H	L
WRITE ALL BYTES	L	L	L
WRITE ABORT/NOP	L	H	H

Notes:

1. X means "Don't Care".
2. All inputs in this table must be setup and hold time around the rising edge of CLK.

WRITE TRUTH TABLE (x32/x36)

Operation	\overline{WE}	$\overline{BW_a}$	$\overline{BW_b}$	$\overline{BW_c}$	$\overline{BW_d}$
READ	H	X	X	X	X
WRITE BYTE a	L	L	H	H	H
WRITE BYTE b	L	H	L	H	H
WRITE BYTE c	L	H	H	L	H
WRITE BYTE d	L	H	H	H	L
WRITE ALL BYTES	L	L	L	L	L
WRITE ABORT/NOP	L	H	H	H	H

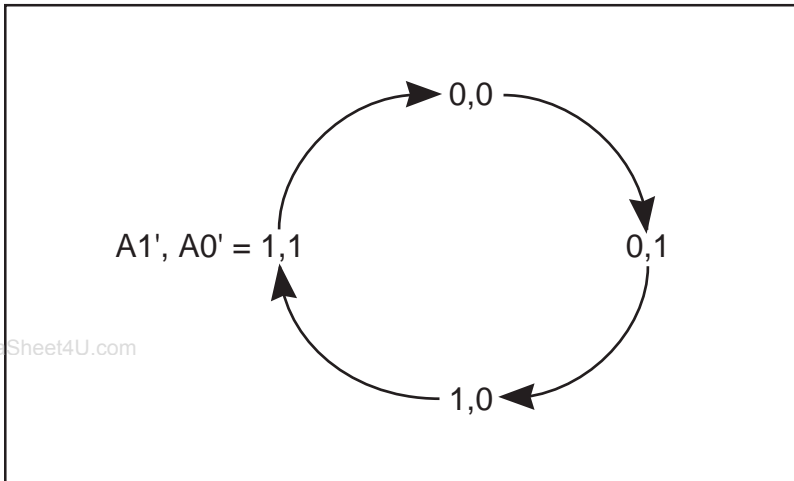
Notes:

1. X means "Don't Care".
2. All inputs in this table must be set up and hold time around the rising edge of CLK.

INTERLEAVED BURST ADDRESS TABLE (MODE = V_{DD} or NC)

External Address A1 A0	1st Burst Address A1 A0	2nd Burst Address A1 A0	3rd Burst Address A1 A0
00	01	10	11
01	00	11	10
10	11	00	01
11	10	01	00

LINEAR BURST ADDRESS TABLE (MODE = V_{SS})



ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Parameter	Value	Unit
T _{STG}	Storage Temperature	-65 to +150	°C
P _D	Power Dissipation	1.6	W
I _{OUT}	Output Current (per I/O)	100	mA
V _{IN} , V _{OUT}	Voltage Relative to V _{SS} for I/O Pins	-0.5 to V _{DDQ} + 0.3	V
V _{IN}	Voltage Relative to V _{SS} for Address and Control Inputs	-0.3 to 4.6	V

Notes:

1. Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
2. This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, precautions may be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.
3. This device contains circuitry that will ensure the output devices are in High-Z at power up.

OPERATING RANGE (IS61NLPx)

Range	Ambient Temperature	V _{DD}	V _{DDQ}
Commercial	0°C to +70°C	3.3V ± 5%	3.3V / 2.5V ± 5%
Industrial	-40°C to +85°C	3.3V ± 5%	3.3V / 2.5V ± 5%

OPERATING RANGE (IS61NVPx)

Range	Ambient Temperature	V _{DD}	V _{DDQ}
Commercial	0°C to +70°C	2.5V ± 5%	2.5V ± 5%
Industrial	-40°C to +85°C	2.5V ± 5%	2.5V ± 5%

DC ELECTRICAL CHARACTERISTICS (Over Operating Range)

Symbol	Parameter	Test Conditions	3.3V		2.5V		Unit
			Min.	Max.	Min.	Max.	
V _{OH}	Output HIGH Voltage	I _{OH} = -4.0 mA (3.3V) I _{OH} = -1.0 mA (2.5V)	2.4	—	2.0	—	V
V _{OL}	Output LOW Voltage	I _{OL} = 8.0 mA (3.3V) I _{OL} = 1.0 mA (2.5V)	—	0.4	—	0.4	V
V _{IH}	Input HIGH Voltage		2.0	V _{DD} + 0.3	1.7	V _{DD} + 0.3	V
V _{IL}	Input LOW Voltage		-0.3	0.8	-0.3	0.7	V
I _{LI}	Input Leakage Current	V _{SS} ≤ V _{IN} ≤ V _{DD} ⁽¹⁾	-5	5	-5	5	μA
I _{LO}	Output Leakage Current	V _{SS} ≤ V _{OUT} ≤ V _{DDQ} , $\overline{OE} = V_{IH}$	-5	5	-5	5	μA

POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	Test Conditions	Temp. range	-250 MAX		-200 MAX		Unit
				x18	x32/x36	x18	x32/x36	
I _{CC}	AC Operating Supply Current	Device Selected, $\overline{OE} = V_{IH}$, ZZ ≤ V _{IL} , All Inputs ≤ 0.2V or ≥ V _{DD} - 0.2V, Cycle Time ≥ t _{kc} min.	Com. Ind.	225 250	225 250	200 210	200 210	mA
I _{SB}	Standby Current TTL Input	Device Deselected, V _{DD} = Max., All Inputs ≤ V _{IL} or ≥ V _{IH} , ZZ ≤ V _{IL} , f = Max.	Com. Ind.	90 100	90 100	90 100	90 100	mA
I _{SBI}	Standby Current CMOS Input	Device Deselected, V _{DD} = Max., V _{IN} ≤ V _{SS} + 0.2V or ≥ V _{DD} - 0.2V f = 0	Com. Ind. typ. ⁽²⁾	70 75 40	70 75	70 75 40	70 75	mA
I _{SB2}	Sleep Mode	ZZ > V _{IH}	Com. Ind. typ. ⁽²⁾	30 35 20	30 35	30 35 20	30 35	mA

Note:

1. MODE pin has an internal pullup and should be tied to V_{DD} or V_{SS}. It exhibits ±100μA maximum leakage current when tied to ≤ V_{SS} + 0.2V or ≥ V_{DD} - 0.2V.
2. Typical values are measured at V_{DD} = 3.3V, T_A = 25°C and not 100% tested.

CAPACITANCE^(1,2)

Symbol	Parameter	Conditions	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	pF
C _{OUT}	Input/Output Capacitance	V _{OUT} = 0V	8	pF

Notes:

1. Tested initially and after any design or process changes that may affect these parameters.
2. Test conditions: T_A = 25°C, f = 1 MHz, V_{DD} = 3.3V.

3.3V I/O AC TEST CONDITIONS

Parameter	Unit
Input Pulse Level	0V to 3.0V
Input Rise and Fall Times	1.5 ns
Input and Output Timing and Reference Level	1.5V
Output Load	See Figures 1 and 2

3.3V I/O OUTPUT LOAD EQUIVALENT

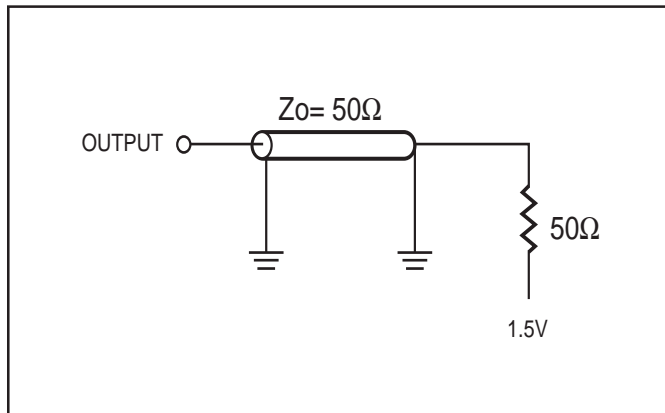


Figure 1

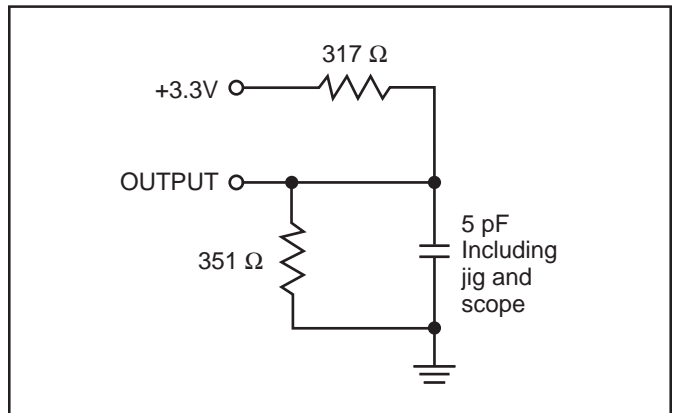


Figure 2

2.5V I/O AC TEST CONDITIONS

Parameter	Unit
Input Pulse Level	0V to 2.5V
Input Rise and Fall Times	1.5 ns
Input and Output Timing and Reference Level	1.25V
Output Load	See Figures 3 and 4

2.5V I/O OUTPUT LOAD EQUIVALENT

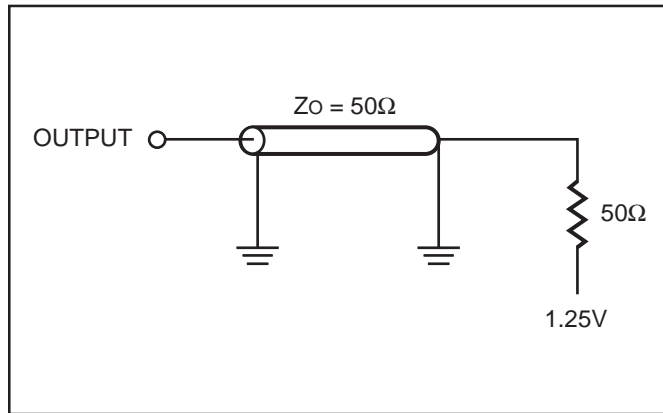


Figure 3

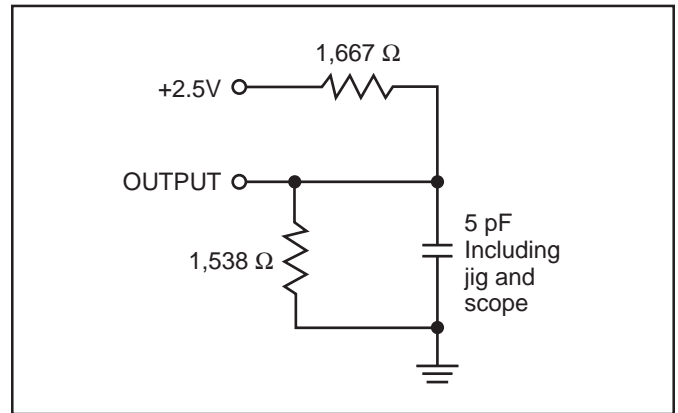


Figure 4

READ/WRITE CYCLE SWITCHING CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	-250		-200		Unit
		Min.	Max.	Min.	Max.	
fmax	Clock Frequency	—	250	—	200	MHz
t _{KC}	Cycle Time	4.0	—	5	—	ns
t _{KH}	Clock High Time	1.7	—	2	—	ns
t _{KL}	Clock Low Time	1.7	—	2	—	ns
t _{KQ}	Clock Access Time	—	2.6	—	3.1	ns
t _{KQX} ⁽²⁾	Clock High to Output Invalid	0.8	—	1.5	—	ns
t _{KQLZ} ^(2,3)	Clock High to Output Low-Z	0.8	—	1	—	ns
t _{KQHZ} ^(2,3)	Clock High to Output High-Z	—	2.6	—	3.0	ns
t _{OEQ}	Output Enable to Output Valid	—	2.8	—	3.1	ns
t _{OELZ} ^(2,3)	Output Enable to Output Low-Z	0	—	0	—	ns
t _{OEHZ} ^(2,3)	Output Disable to Output High-Z	—	2.6	—	3.0	ns
t _{AS}	Address Setup Time	1.2	—	1.4	—	ns
t _{WS}	Read/Write Setup Time	1.2	—	1.4	—	ns
t _{CES}	Chip Enable Setup Time	1.2	—	1.4	—	ns
t _{SE}	Clock Enable Setup Time	1.2	—	1.4	—	ns
t _{ADVS}	Address Advance Setup Time	1.2	—	1.4	—	ns
t _{DS}	Data Setup Time	1.2	—	1.4	—	ns
t _{AH}	Address Hold Time	0.3	—	0.4	—	ns
t _{HE}	Clock Enable Hold Time	0.3	—	0.4	—	ns
t _{WH}	Write Hold Time	0.3	—	0.4	—	ns
t _{CEH}	Chip Enable Hold Time	0.3	—	0.4	—	ns
t _{ADVH}	Address Advance Hold Time	0.3	—	0.4	—	ns
t _{DH}	Data Hold Time	0.3	—	0.4	—	ns
t _{PDS}	ZZ High to Power Down	—	2	—	2	cyc
t _{PUS}	ZZ Low to Power Down	—	2	—	2	cyc

Notes:

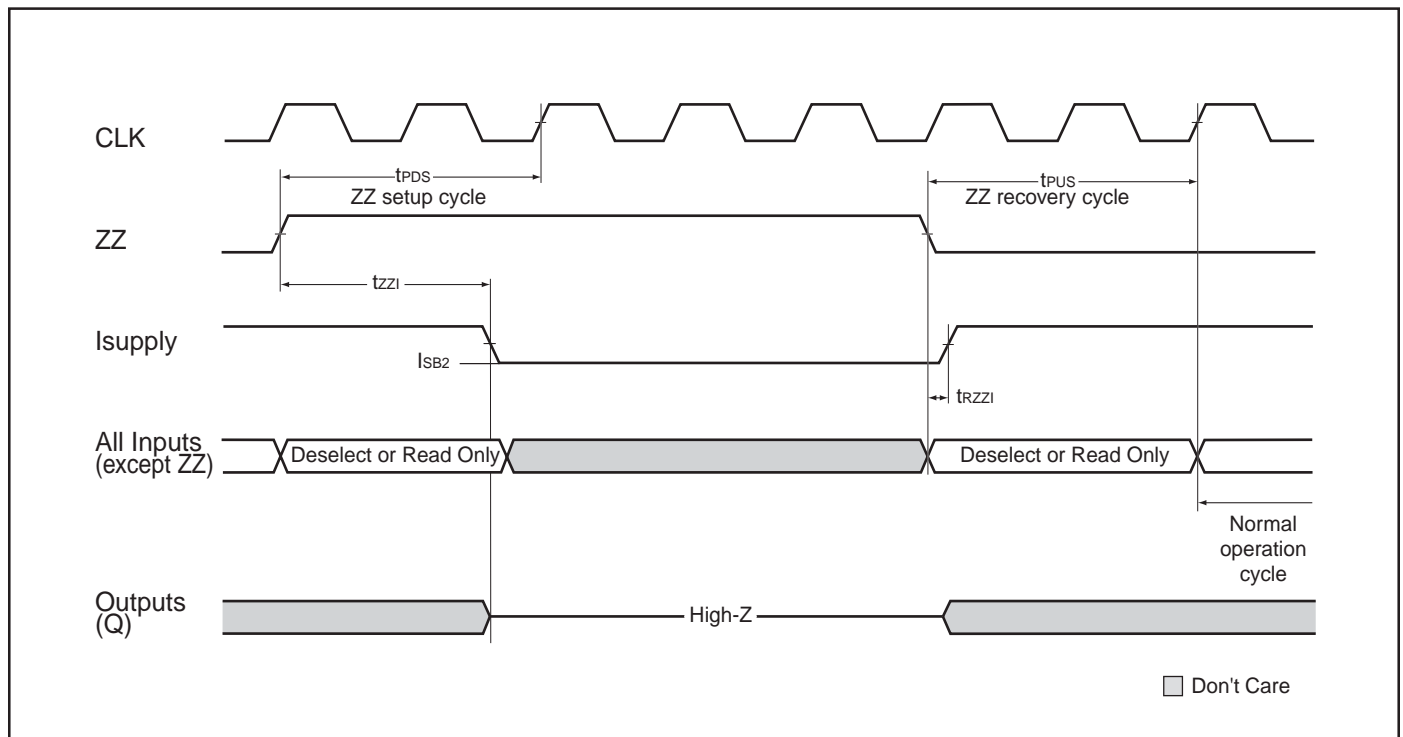
1. Configuration signal MODE is static and must not change during normal operation.
2. Guaranteed but not 100% tested. This parameter is periodically sampled.
3. Tested with load in Figure 2.

SLEEP MODE ELECTRICAL CHARACTERISTICS

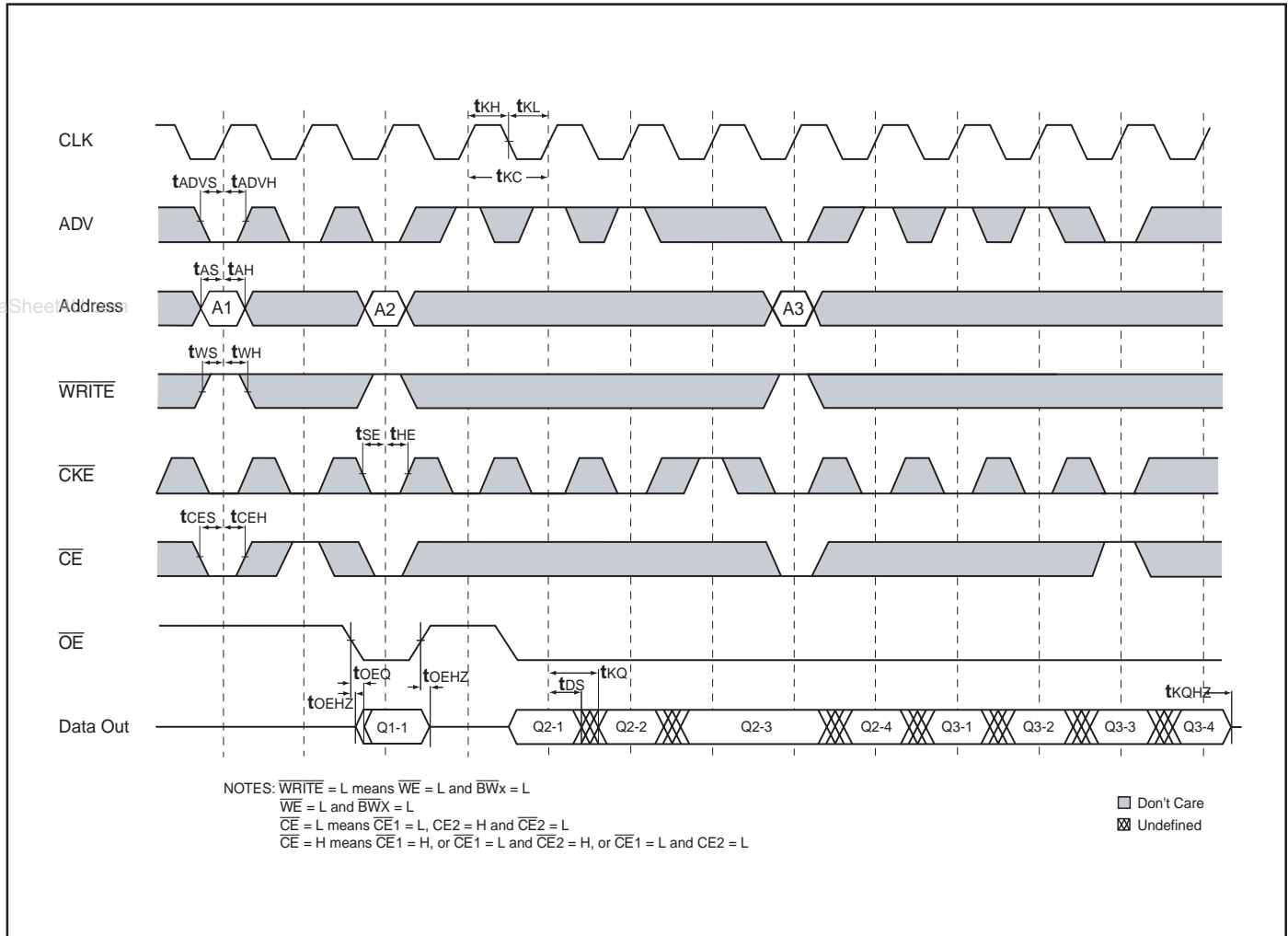
Symbol	Parameter	Conditions	Min.	Max.	Unit
I _{SB2}	Current during SLEEP MODE	ZZ ≥ V _{IH}		35	mA
t _{PDS}	ZZ active to input ignored		2		cycle
t _{PUS}	ZZ inactive to input sampled		2		cycle
t _{ZZI}	ZZ active to SLEEP current		2		cycle
t _{TRZI}	ZZ inactive to exit SLEEP current		0		ns

www.DataSheet4U.com

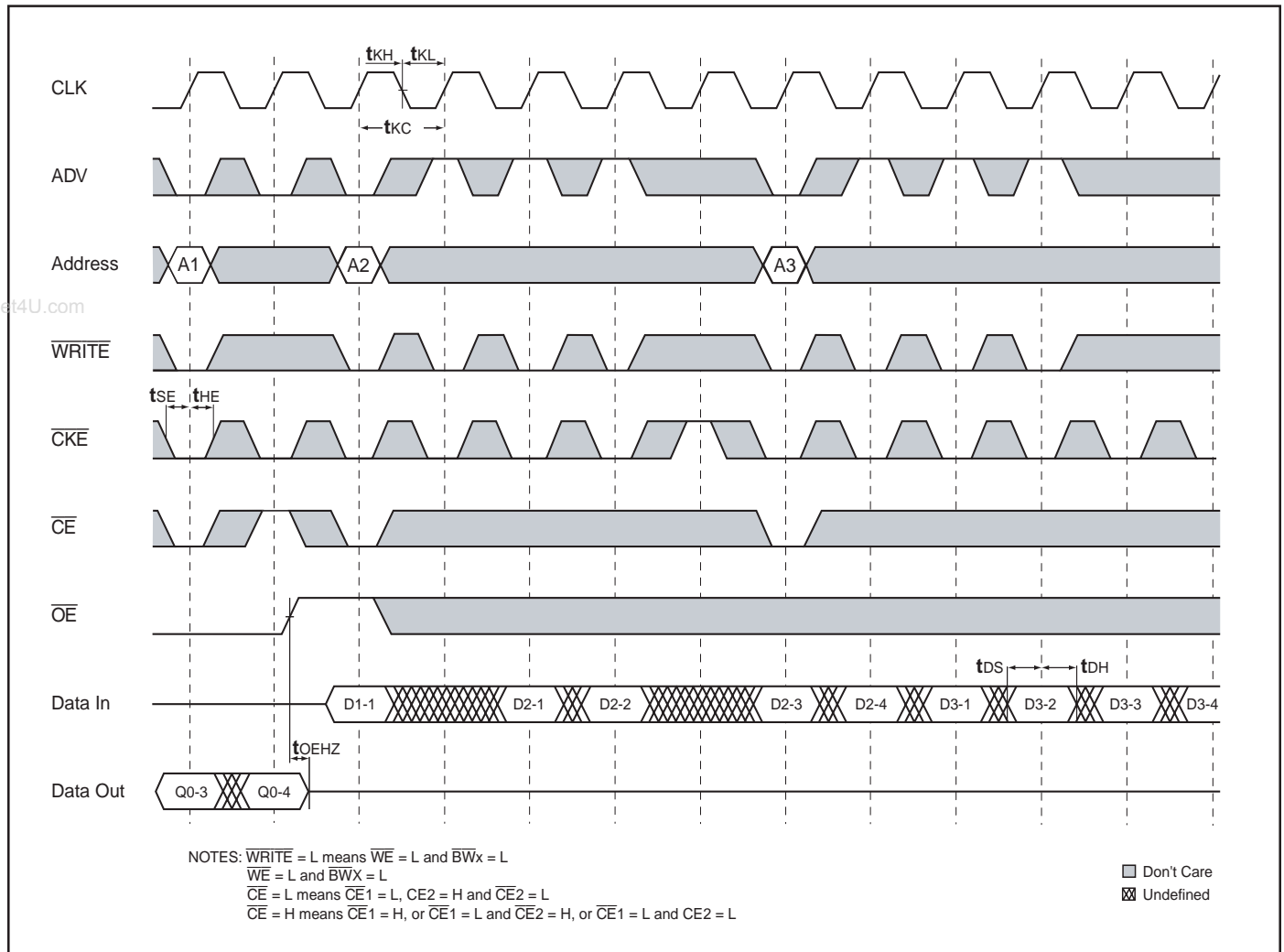
SLEEP MODE TIMING



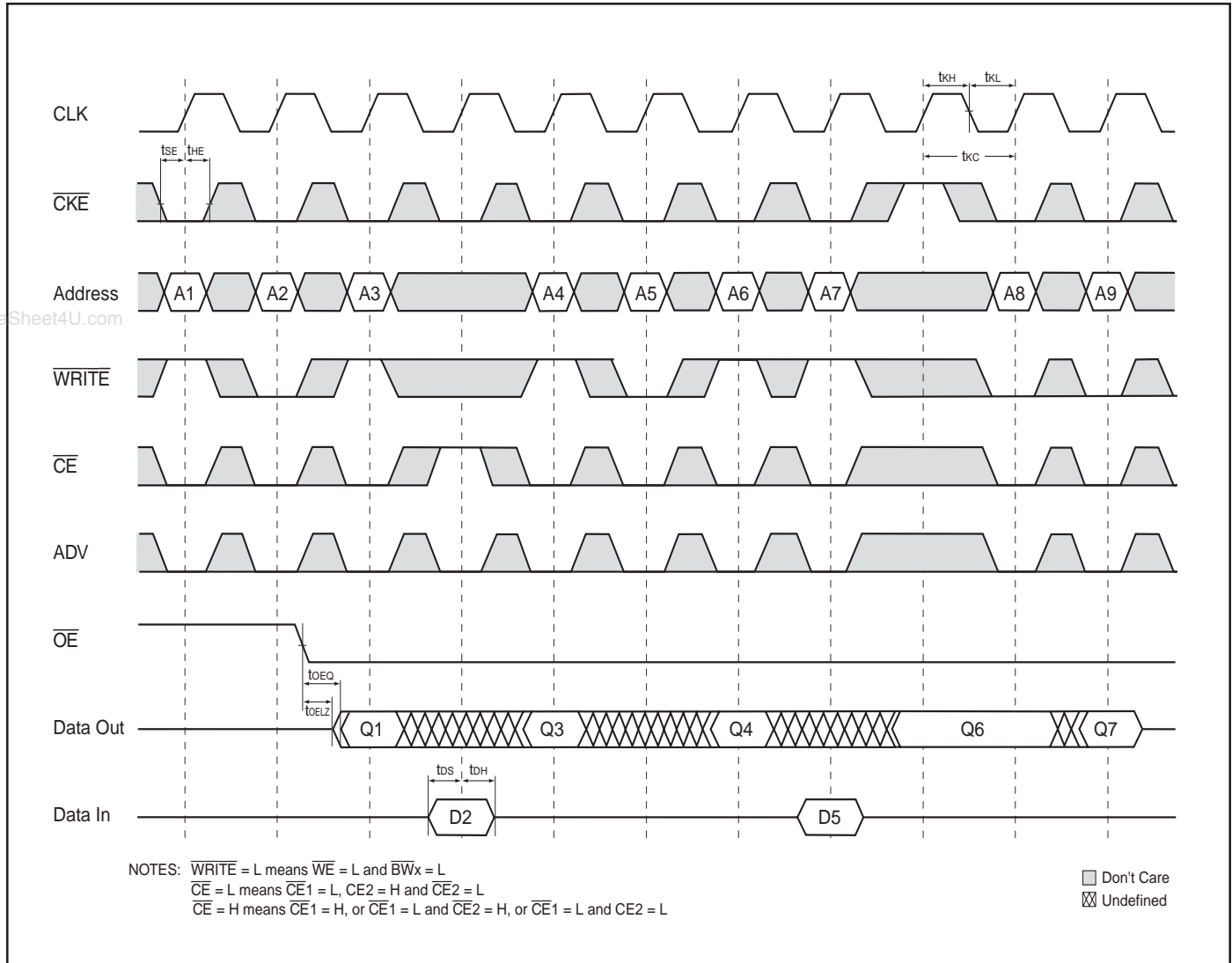
READ CYCLE TIMING



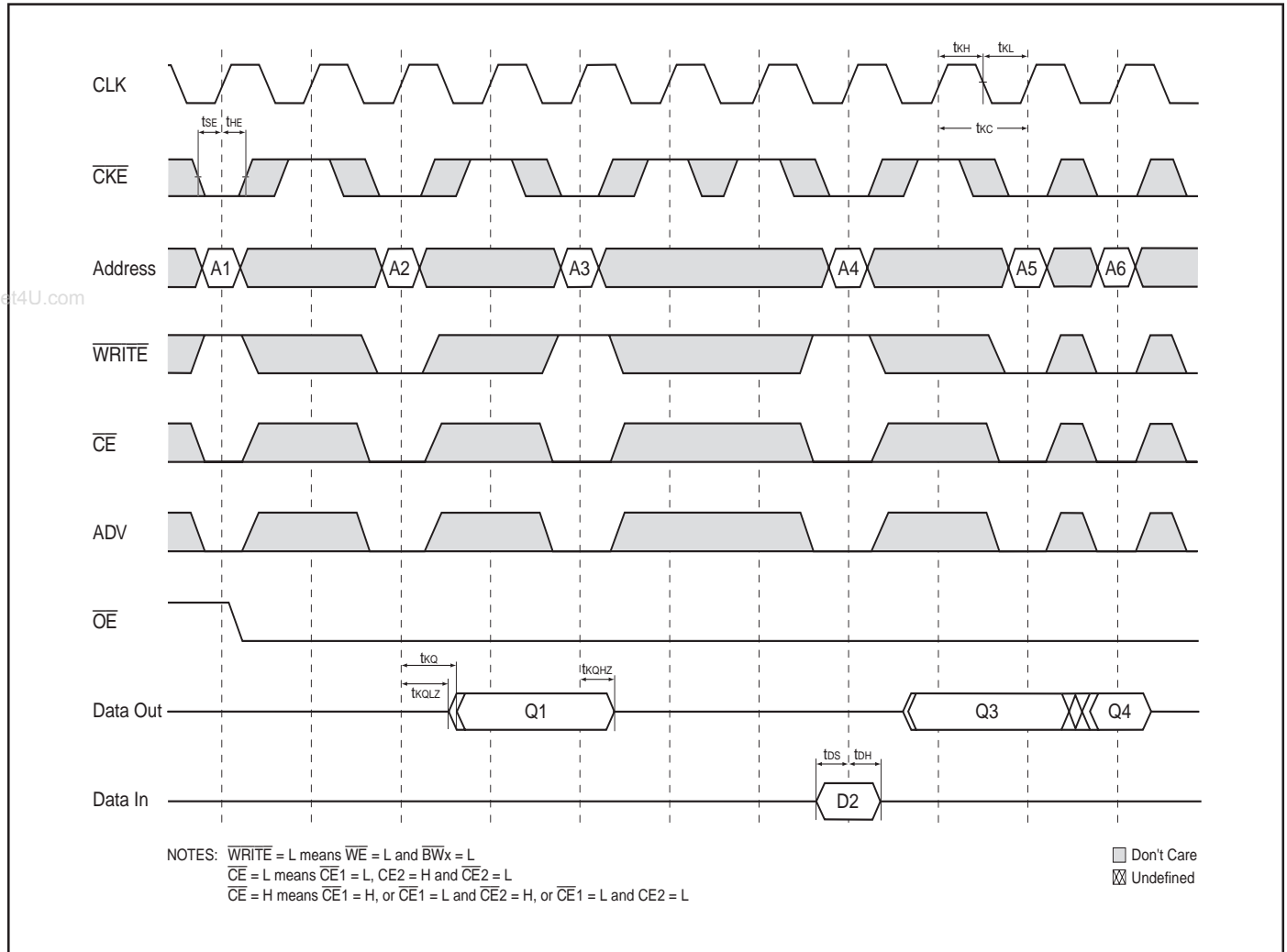
WRITE CYCLE TIMING



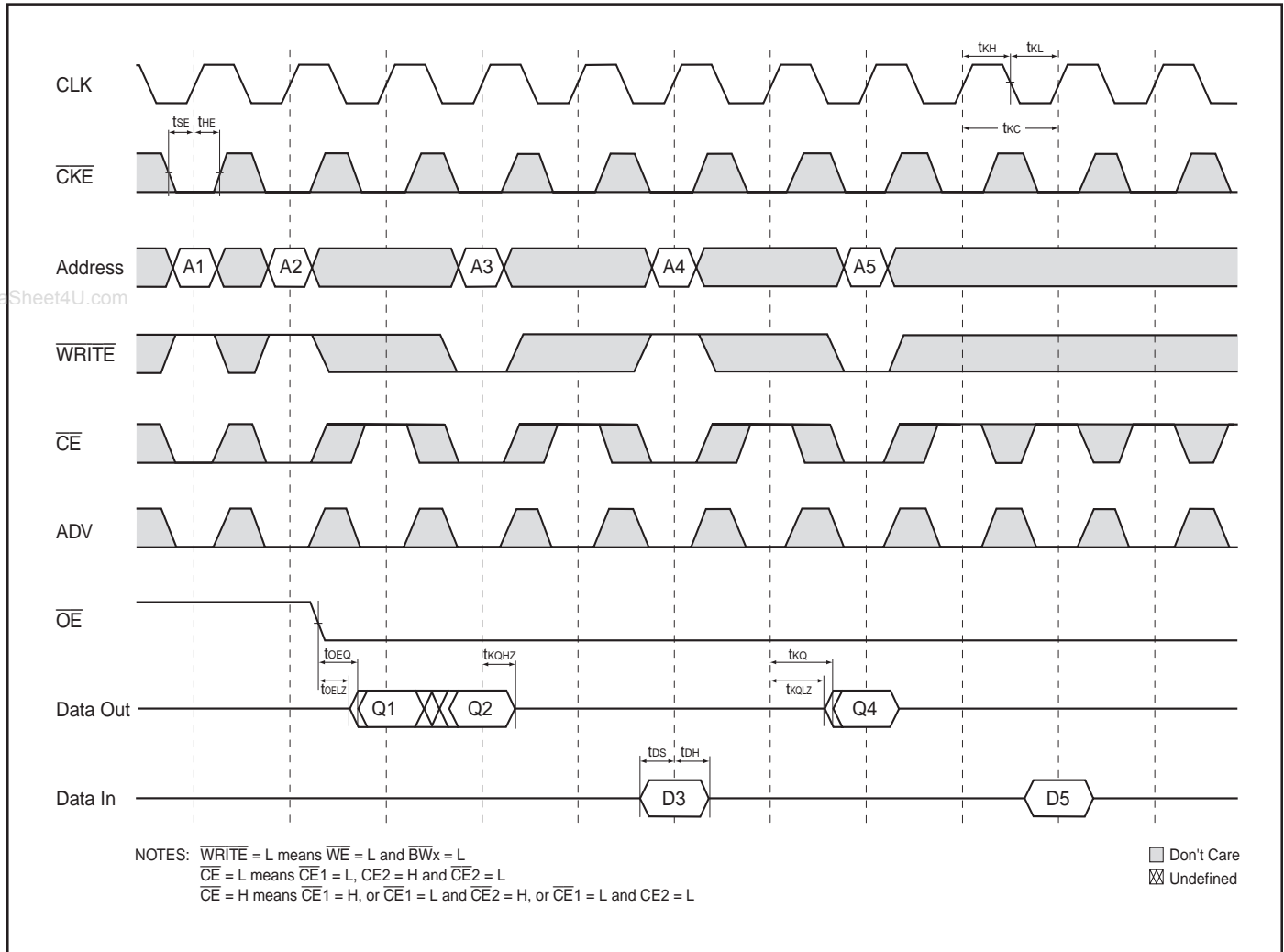
SINGLE READ/WRITE CYCLE TIMING



CKE OPERATION TIMING



CE OPERATION TIMING



ORDERING INFORMATION ($V_{DD} = 3.3V/V_{DDQ} = 2.5V/3.3V$)

Commercial Range: 0°C to +70°C

Access Time	Order Part Number	Package
64Kx32		
250	IS61NLP6432A-250TQ	100 TQFP
200	IS61NLP6432A-200TQ	100 TQFP
64Kx36		
250	IS61NLP6436A-250TQ	100 TQFP
200	IS61NLP6436A-200TQ	100 TQFP
128Kx18		
250	IS61NLP12818A-250TQ	100 TQFP
200	IS61NLP12818A-200TQ	100 TQFP

Industrial Range: -40°C to +85°C

Access Time	Order Part Number	Package
64Kx32		
250	IS61NLP6432A-250TQI	100 TQFP
200	IS61NLP6432A-200TQI	100 TQFP
200	IS61NLP6432A-200TQLI	100 TQFP, Lead-free
64Kx36		
250	IS61NLP6436A-250TQI	100 TQFP
200	IS61NLP6436A-200TQI	100 TQFP
128Kx18		
250	IS61NLP12818A-250TQI	100 TQFP
200	IS61NLP12818A-200TQI	100 TQFP
200	IS61NLP12818A-200TQLI	100 TQFP, Lead-free

ORDERING INFORMATION (V_{DD} = 2.5V/V_{DDQ} = 2.5V)

Commercial Range: 0°C to +70°C

Access Time	Order Part Number	Package
64Kx36		
250	IS61NVP6436A-250TQ	100 TQFP
200	IS61NVP6436A-200TQ	100 TQFP
128Kx18		
250	IS61NVP12818A-250TQ	100 TQFP
200	IS61NVP12818A-200TQ	100 TQFP

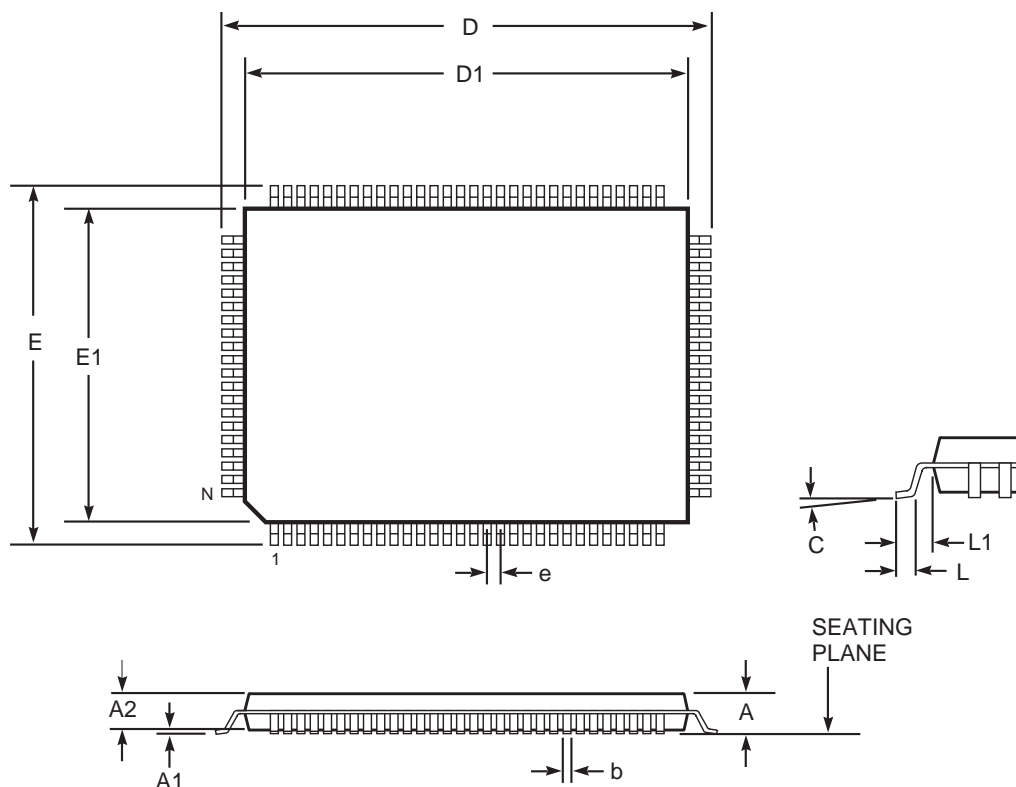
Industrial Range: -40°C to +85°C

Access Time	Order Part Number	Package
64Kx36		
250	IS61NVP6436A-250TQI	100 TQFP
200	IS61NVP6436A-200TQI	100 TQFP
128Kx18		
250	IS61NVP12818A-250TQI	100 TQFP
200	IS61NVP12818A-200TQI	100 TQFP

PACKAGING INFORMATION

TQFP (Thin Quad Flat Pack Package)

Package Code: TQ



Thin Quad Flat Pack (TQ)									
Symbol	Millimeters		Inches		Symbol	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
Ref. Std.									
No. Leads (N)	100				128				
A	—	1.60	—	0.063	—	1.60	—	0.063	
A1	0.05	0.15	0.002	0.006	0.05	0.15	0.002	0.006	
A2	1.35	1.45	0.053	0.057	1.35	1.45	0.053	0.057	
b	0.22	0.38	0.009	0.015	0.17	0.27	0.007	0.011	
D	21.90	22.10	0.862	0.870	21.80	22.20	0.858	0.874	
D1	19.90	20.10	0.783	0.791	19.90	20.10	0.783	0.791	
E	15.90	16.10	0.626	0.634	15.80	16.20	0.622	0.638	
E1	13.90	14.10	0.547	0.555	13.90	14.10	0.547	0.555	
e	0.65 BSC		0.026 BSC		0.50 BSC		0.020 BSC		
L	0.45	0.75	0.018	0.030	0.45	0.75	0.018	0.030	
L1	1.00 REF.		0.039 REF.		1.00 REF.		0.039 REF.		
C	0°	7°	0°	7°	0°	7°	0°	7°	

Notes:

1. All dimensioning and tolerancing conforms to ANSI Y14.5M-1982.
2. Dimensions D1 and E1 do not include mold protrusions. Allowable protrusion is 0.25 mm per side. D1 and E1 do include mold mismatch and are determined at datum plane -H-.
3. Controlling dimension: millimeters.